

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/784,798	PARK ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Ingrid Wright	2835	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0070348 A1	03-2005	Lee et al.	455/575.4
	B	US-6,614,650 B2	09-2003	Tabata, Taichi	361/681
	C	US-2005/0160558 A1	07-2005	Kim, Ju-Hee	016/367
	D	US-2005/0079902 A1	04-2005	Chen et al.	455/575.4
	E	US-2003/0174240 A1	09-2003	Wada et al.	348/374
	F	US-6,539,208 B1	03-2003	Mori, Tatsuya	455/575.3
	G	US-6,496,365 B2	12-2002	Tsai, Huo-Lu	361/686
	H	US-6,392,881 B1	05-2002	Saitoh, Asao	361/686
	I	US-2004/0137940 A1	07-2004	Matsunami, Kanako	455/550.1
	J	US-6,822,871 B2	11-2004	Lee et al.	361/727
	K	US-2003/0064688 A1	04-2003	Mizuta et al.	455/90
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2384389 A	07-2003	United Kingdom	INOUE et al.	H04M 01/02
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.